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Supporting information for article:

Development of a crystal collimation system for high-resolution ultra-small-angle X-ray scattering applications

Michael Sztucki, Joachim Leonardon, Pierre Van Vaerenbergh, Jacques Gorini, Peter Boesecke and Theyencheri Narayanan

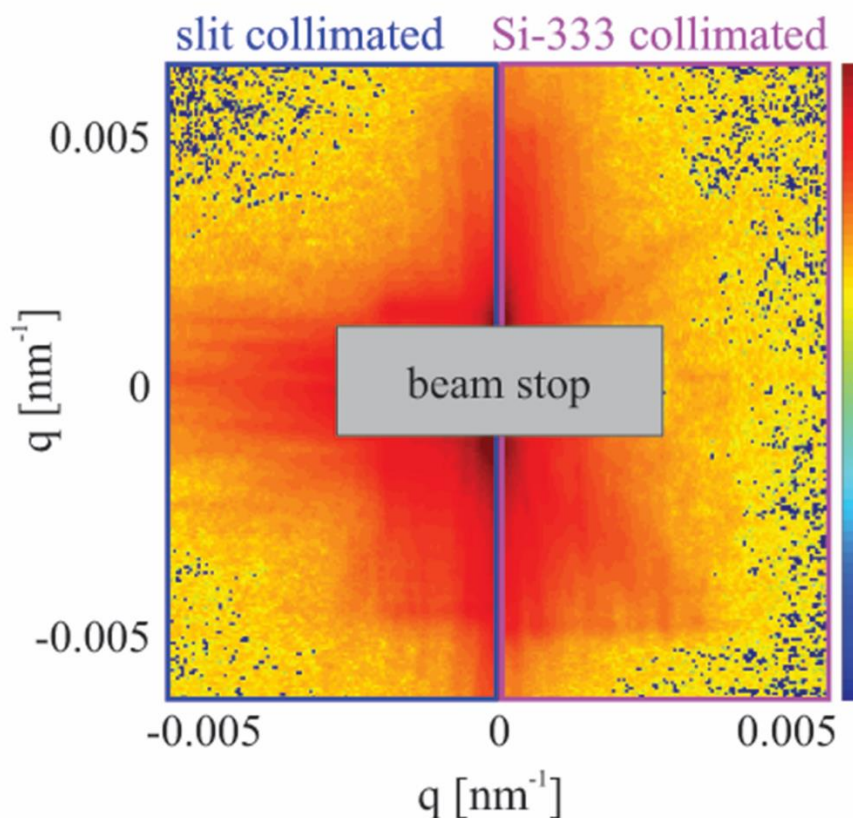


Figure S1 Composite image of the parasitic scattering in vertical and horizontal direction in logarithmic scale measured at an X-ray energy of 12460 eV (~ 0.0995 nm) at 96 m from the source. The left half shows the parasitic scattering of a beam which is moderately slit collimated [configuration (A)], the right half the scattering after horizontal Si-333 crystal collimation [configuration (B)]. The crystal collimated beam has a much lower parasitic scattering close to the beamstop [2.5 mm(h) x 0.9 mm(v)] as compared to the only slit collimated beam which is of great significance to reach lowest possible scattering angles in USAXS. The vertical beam profile is basically not changed between the two configurations.